

<b>Notice of References Cited</b>	Application/Control No. 10/033,891	Applicant(s)/Patent Under Reexamination YEN ET AL.
	Examiner Peter B. Kim	Art Unit 2851

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,703,675	12-1997	Hirukawa et al.	355/53
	B	US-2003/0103196	06-2003	Hirukawa, Shigeru	355/55
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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